

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Named Inventor: HAPKE, Friedrich

Docket No.: DE02 0018 US

PTO Application No.: Conf.:

Art Unit:

Date Filed:

Examiner:

Title: Integrated Circuit With Self-Testing Circuit

Mail Stop DD

Commissioner for Patents

P.O. Box 1450, Alexandria, VA 22313-1450

**TRANSMITTAL OF  
INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR §1.97**

Sir:

Enclosed in this transmittal is an "Information Disclosure Statement by Applicant" and a copy of each of the documents listed thereon. These documents are considered to be relevant in that they have been cited as an "X" or "Y" document in a foreign Patent Office search report on a foreign counterpart application, a copy of which report is also enclosed.

☐ I hereby certify that these documents were cited in said search report not more than three (3) months prior to the filing of this information disclosure statement.

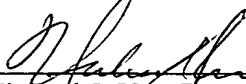
This disclosure is not an admission that any of these documents is material to or even prior art with respect to the above-referenced application.

The Commissioner is hereby requested and authorized pursuant to 37 CFR §1.136(a)(3), to treat any concurrent or future reply in this application requiring a petition for extension of time for its timely submission, as incorporating a petition for extension of time for the appropriate length of time. Please charge any additional fees which may now or in the future be required in this application, including extension of time fees, but excluding the issue fee unless explicitly requested to do so, and credit any overpayment, to Deposit Account No. 14-1270.

Date: 7/14/04

Respectfully submitted,

By



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**CERTIFICATE OF MAILING**

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage for first class mail in an envelope addressed to "Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450" on the date indicated below.

(Date)

16-JUL-04

(Signature)

(Name)

  
Daniel L. Michalek

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>	<b>Application Number</b>	
	<b>Filing Date</b>	
	<b>First Named Inventor</b>	HAPKE, Friedrich
	<b>Art Unit</b>	
	<b>Examiner Name</b>	
	<b>Attorney Docket Number</b>	DE02 0018 US

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number No.-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number (ctry <sup>3</sup> -no. <sup>4</sup> -kind <sup>5</sup> , if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of cited document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear
		EP 1 178 322	02-06-2002	HAPKE, FRIEDRICH	
		WO 01 038889	05-31-2001	RAJSKI, JANUSZ, ET AL.	

NON-PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in capital letters), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>6</sup>
		KIEFER, G, ET AL. "USING BIST CONTROL FOR PATTERN GENERATION" PROCEEDINGS OF THE INTERNATIONAL TEST CONF. ITC '97. WASHINGTON, DC NO. 1-6, 1997, INTERNATIONAL TEST CONF., NEW YORK, NY: IEEE, US, VOL. CONF. 28, 1 NOVEMBER 1997	

<b>Examiner Signature</b>		<b>Date Considered</b>	
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\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup> Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.